

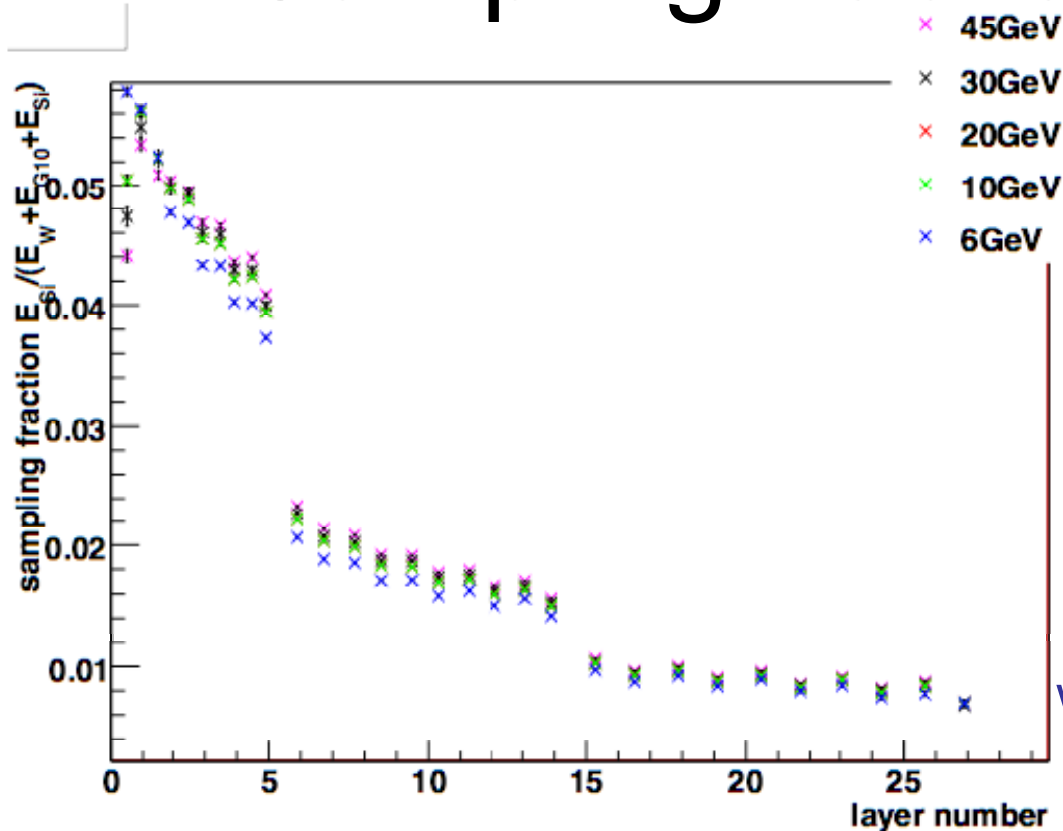
# Longitudinal shower profile - CERN electron runs 2006 -

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# Sampling fraction

- Allow sampling fraction  $f_{\text{samp}}$  to vary layer by layer
  - Take into account variation of energy deposition if energy of electrons in the shower is so low that they do not dominantly do bremsstrahlung
- Estimate sampling fraction  $f_{\text{samp}}$  with MC simulation
$$F_{\text{samp}} = E_{\text{dep active}} / E_{\text{dep total}}$$
- For  $E_{\text{dep total}}$  only W and G10 used  
for 30GeV 96% of  $E_{\text{dep total}}$  deposited in W, Si and G10
- Needed to write new MOKKA driver for this  
with the help of Gabriel Musat
- Resulting files large (50GB for 1000 events) due to structure of LCIO

# Sampling fraction



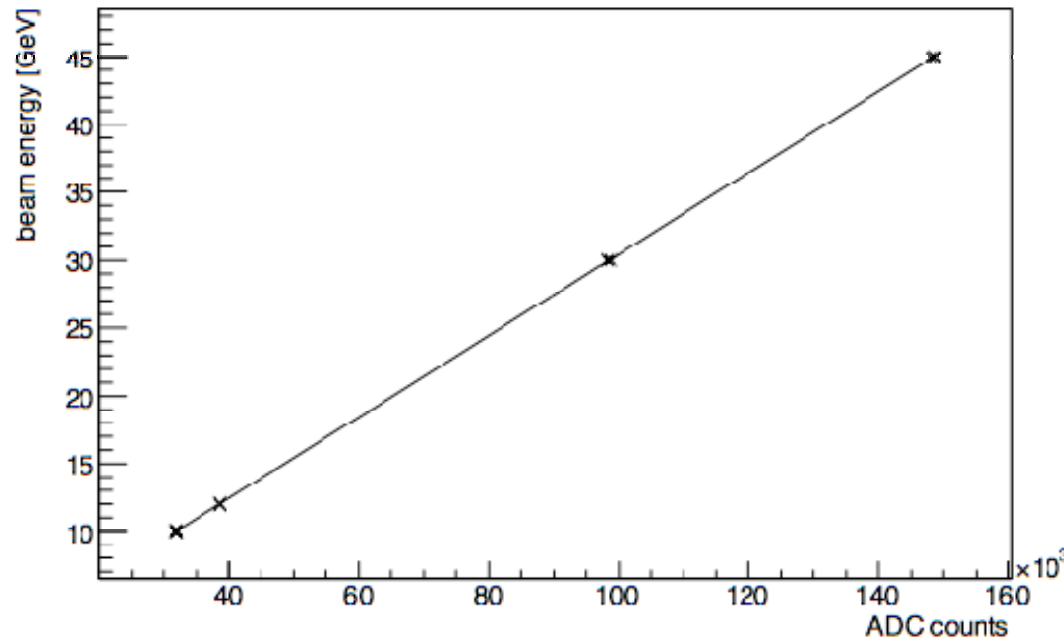
written up in CIN-013

- One can see odd/even layer difference
- 3 stack with differing W thickness
- However ratio between the stack is: 1/1.8/2.6 instead of 1/2/3 (also supported when carefully adding all radiation lengths)

# Sampling fraction

- New sampling fraction also takes care of odd/even layer difference
- Changes between odd/even layer and this method:
  - Shower max
  - Leakage Energy
  - Small change of the  $\chi^2$  of the fits to the longitudinal profile

# Linearity



$$\chi^2 = 0.5$$

Fit:

$$E_{\text{beam}} = \text{ADC\_counts} * (2.97 \pm 0.03) * 10^{-4}$$

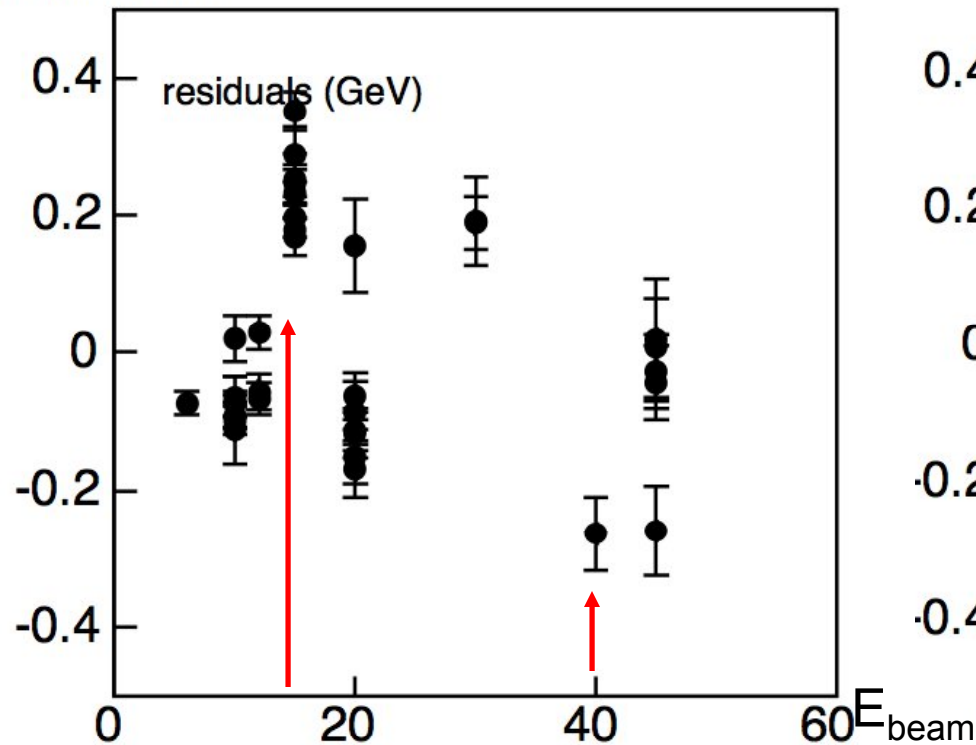
$\Rightarrow$  need new mip\_conv for this method

# However looking closer....

(plots from Daniel Jeans)

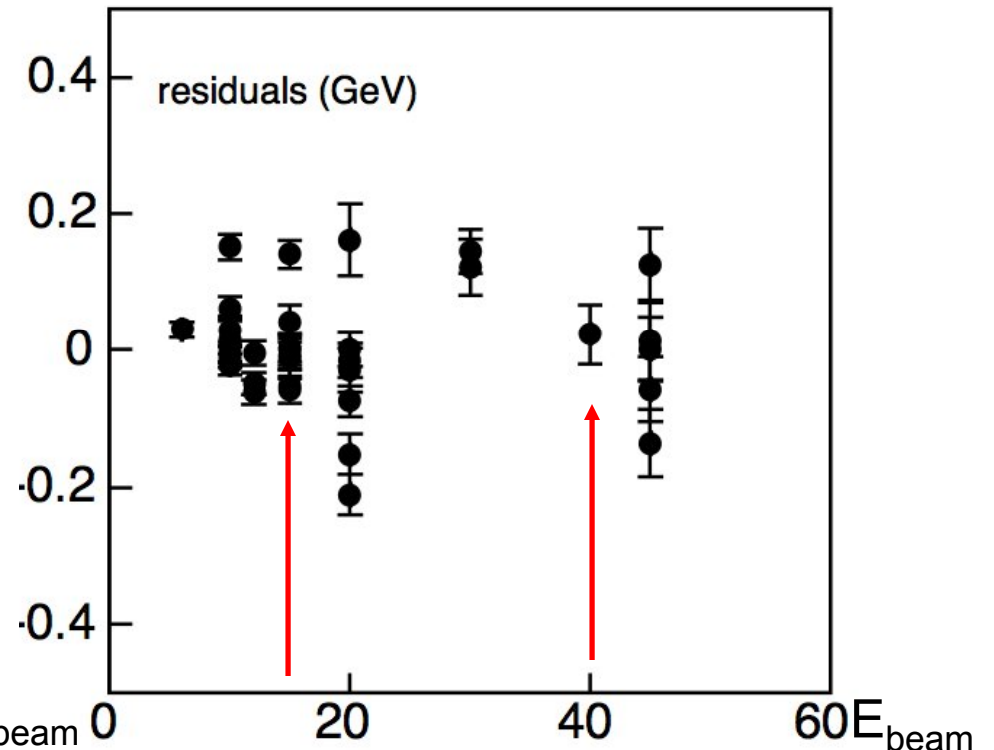
New sampling fraction

residualValeria



Odd/even layer correction

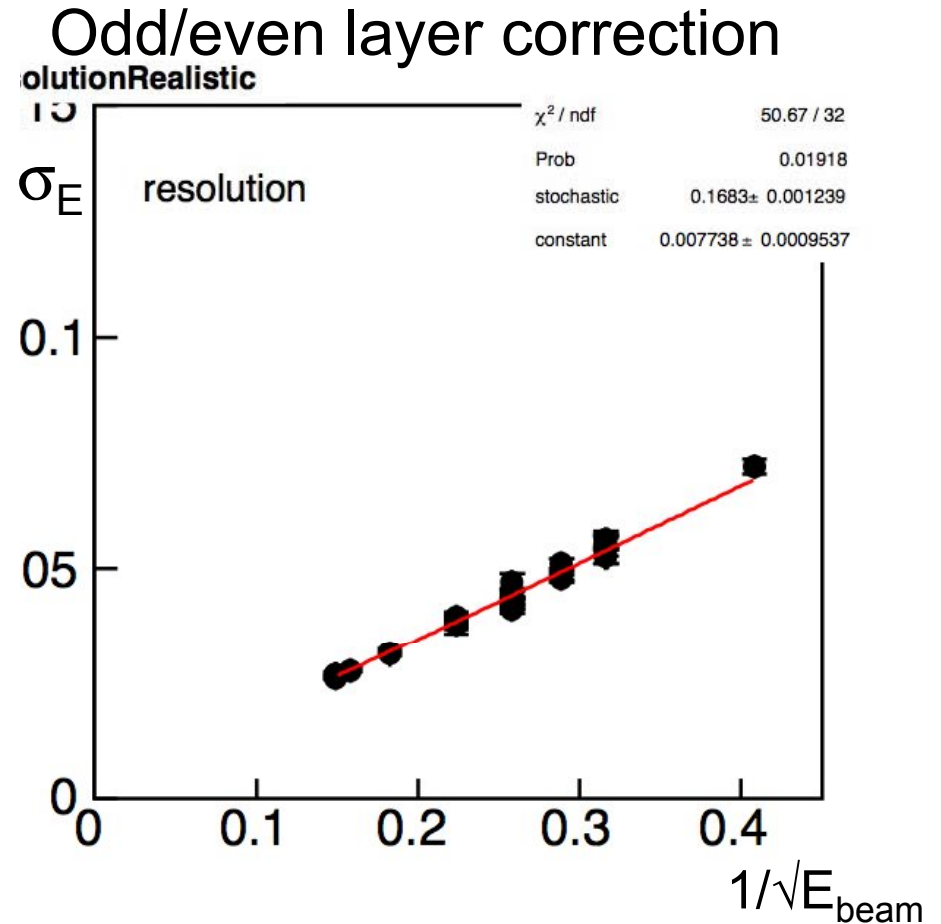
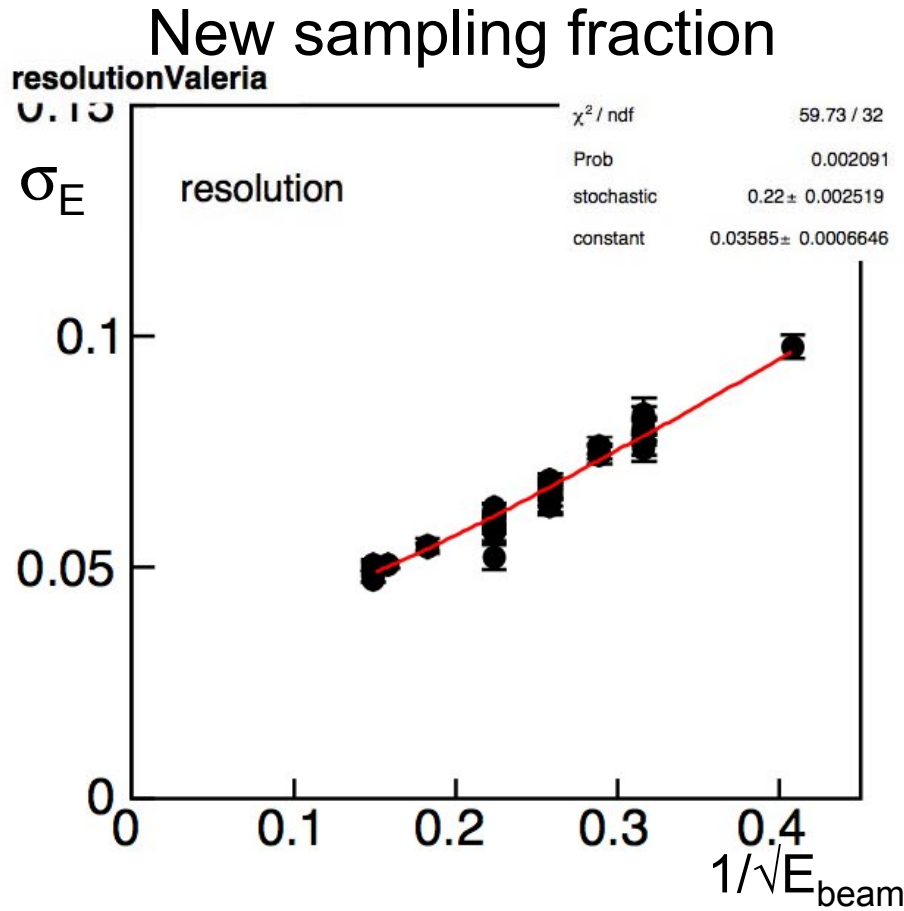
residualRealistic



⇒ Residual are higher for 15 GeV (no correct sampling fraction for this energy) and 40 GeV

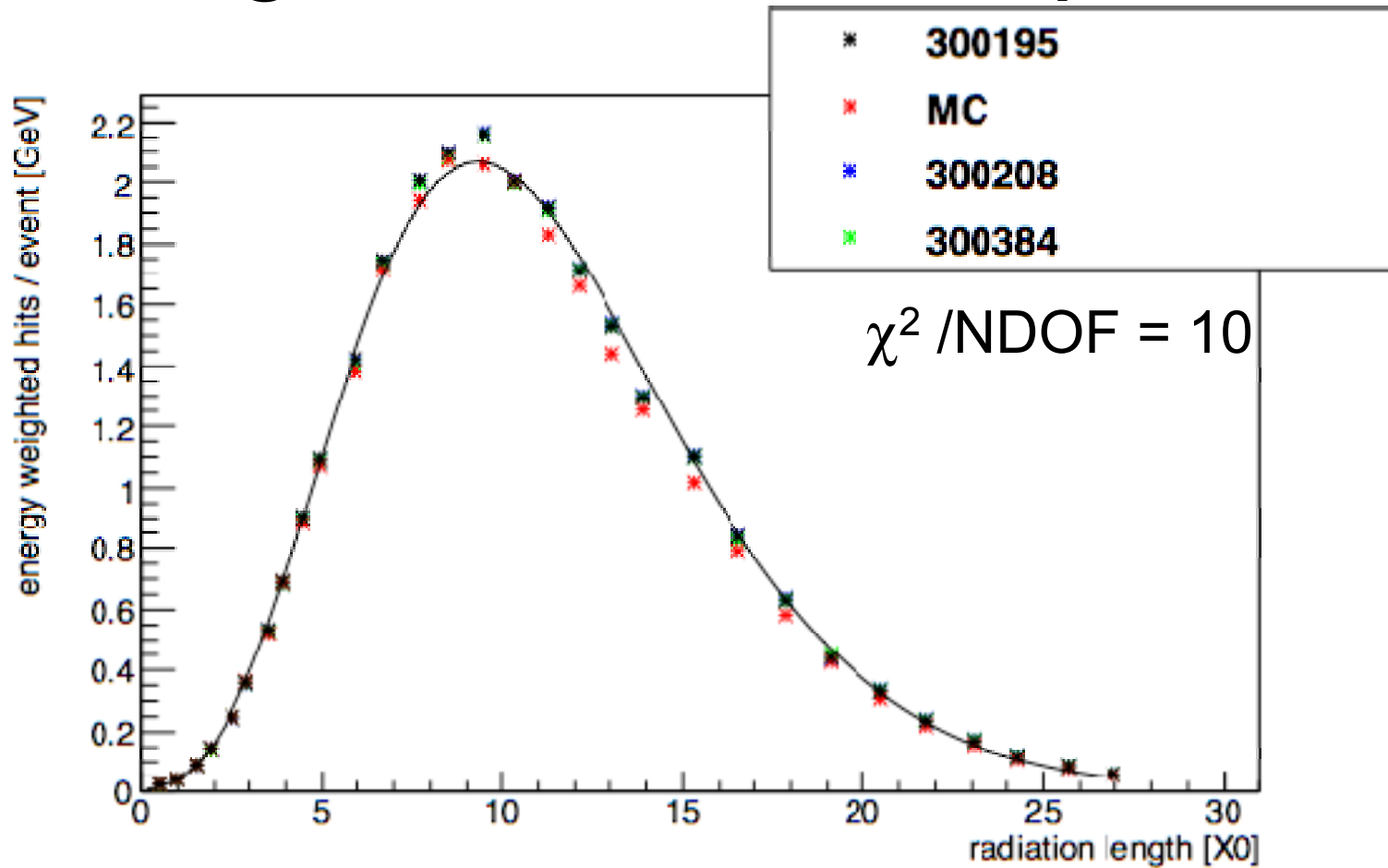
# However looking closer....

(plots from Daniel Jeans)



⇒ Effect on resolution not understood yet

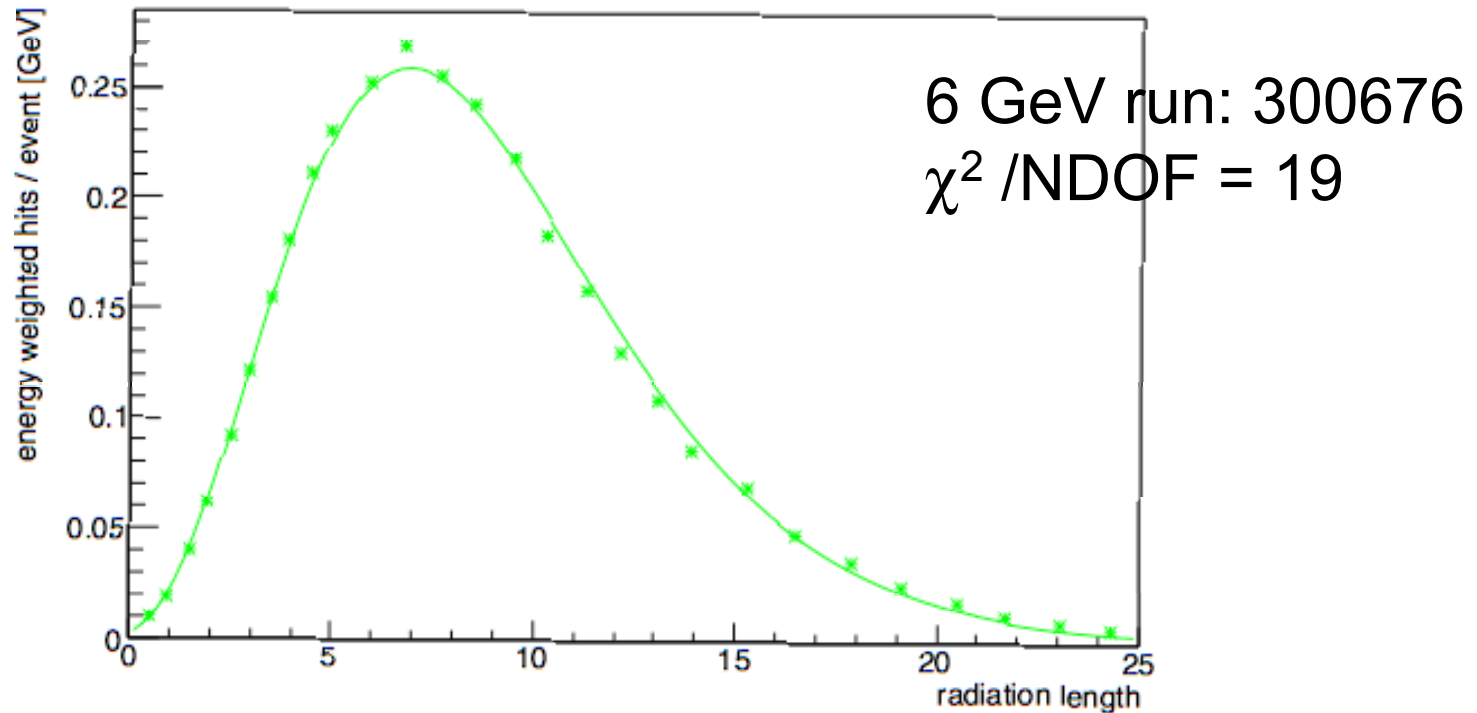
# Longitudinal shower profile



new G10 density solved disagreement between MC and data



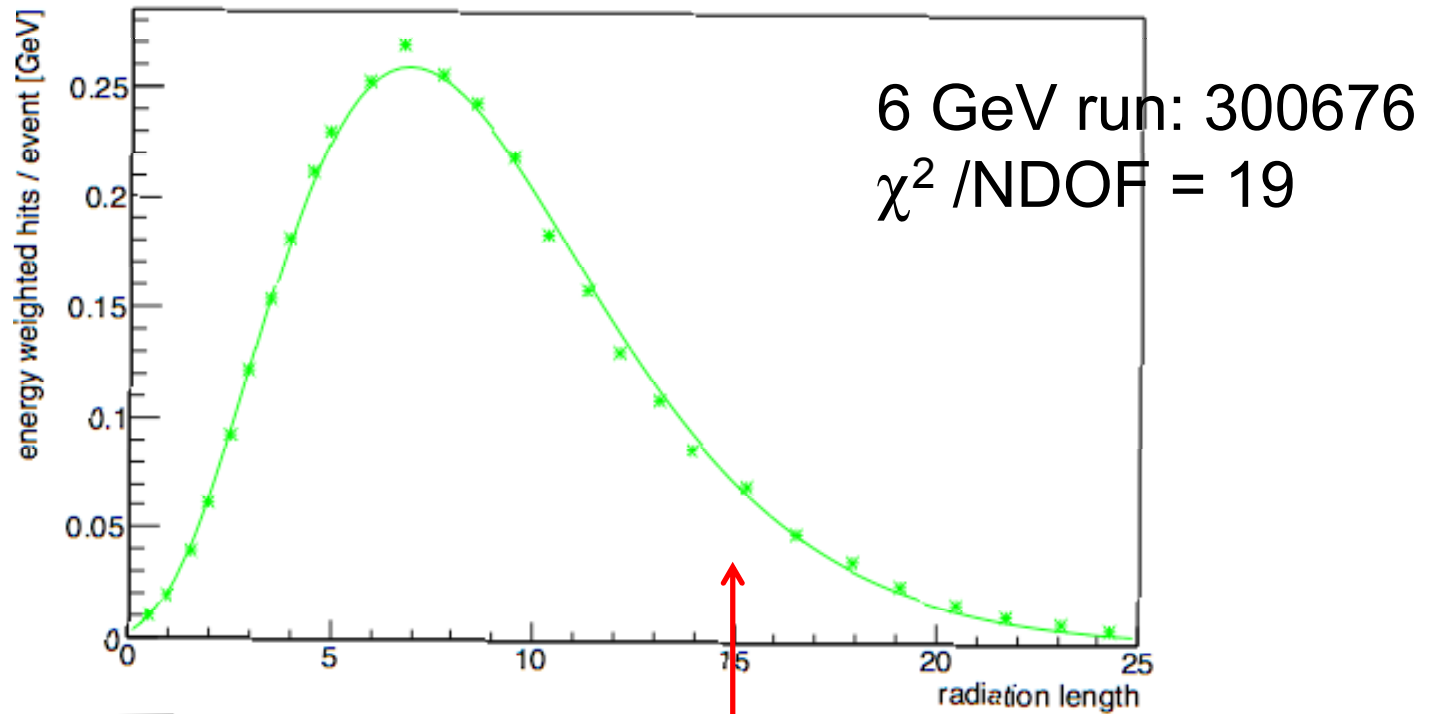
# Parameters to extract from profile



- Fitted with:  
$$f(X_0) = \text{Const.} (X_0 - \beta)^\alpha \exp(-0.5 (X_0 - \beta))$$
- Interesting parameters to extract:
  - leakage energy
  - shower max
  - material in front of calo  $\beta$

# Parameters to extract from profile

## Side remark



For data of all energies this layer is always high  
(checked that this is not true for MC)

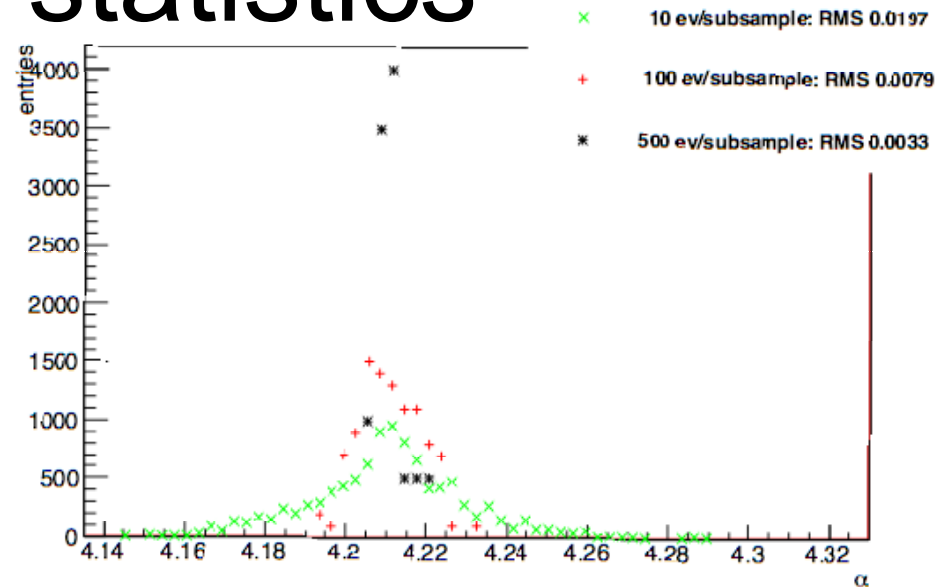
⇒ Could come from noise

# Some statistics

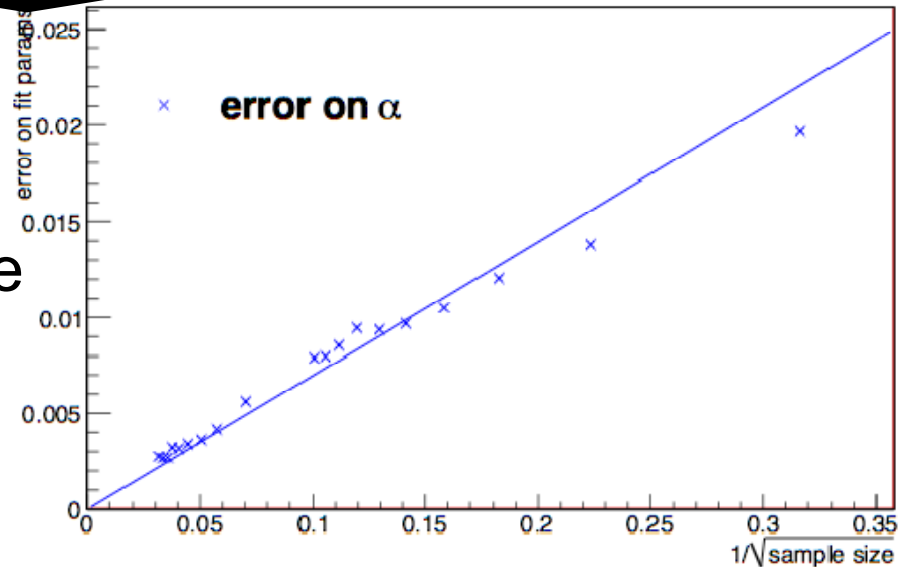
- Some of the parameters to extract from the fit are not identical with the fit parameters:
    - $E_{\text{leakage}}$  = integral from  $X_0=26$ -infinity
    - Shower maximum = maximum of the distribution
  - Errors on the MINUIT fit parameters not equal to errors on these parameters
- ⇒ Used a different method which splits the sample into subsamples to extract errors of the leakage energy and the shower maximum
- ⇒ first need to show that this method works

# Some statistics

- Get RMS on distribution of each fit parameter (later of the integral..)
- Change subsample size



- Plot against subsample size



# Comparison with MINUIT errors

Fit parameter	$\sigma$	$\sigma_{\text{MINUIT}}$
$\alpha$	$7.0 \cdot 10^{-4}$	$6.7 \cdot 10^{-4}$
$\beta$	$2.90 \cdot 10^{-4}$	$2.89 \cdot 10^{-4}$
$\gamma$	$5.3 \cdot 10^{-5}$	$5.1 \cdot 10^{-5}$

- Statistical error can be extracted like this
- Systematics:  $\sigma_{\text{sys+stat}} = \text{const.} \cdot \sigma_{\text{stat}}$

# Systematic errors ...

- Effect from error on calibration:
  - 0.4% from statistical error
  - 0.5% from systematic for 99.1% of all channels

See Anne Marie's paper

  - These errors both add up to give the systematic error which is not correlated:

$\Rightarrow \sigma_{\text{sys calib}} = 0.9\% / \sqrt{\text{no of cells}}$

# More on systematic errors

- Statistical error on sampling fraction:
  - Can be up to 4% for first layers due to small number of hits
    - ⇒ create more MC for sampling fraction
  - Usually less than 0.5%
- Small effect from
  - Error on beam energy
    - e.g. 450MeV largest uncertainty for 45GeV
  - Rotation of the detector
  - Error on collimator settings

# Systematic error

- $\sigma_{\text{sys+stat}} = \text{const.} \cdot \sigma_{\text{stat}}$
- Const. = 5 on average, depending on run
- Const. the same for all fit parameter

⇒ Add sys errors in following plots



# $\chi^2$ on fits

- Only after determining the errors correctly the  $\chi^2$  of the fits makes sense
- Comparison the  $\chi^2$  of data to MC:

e.g. run 300676: 19/NDOF

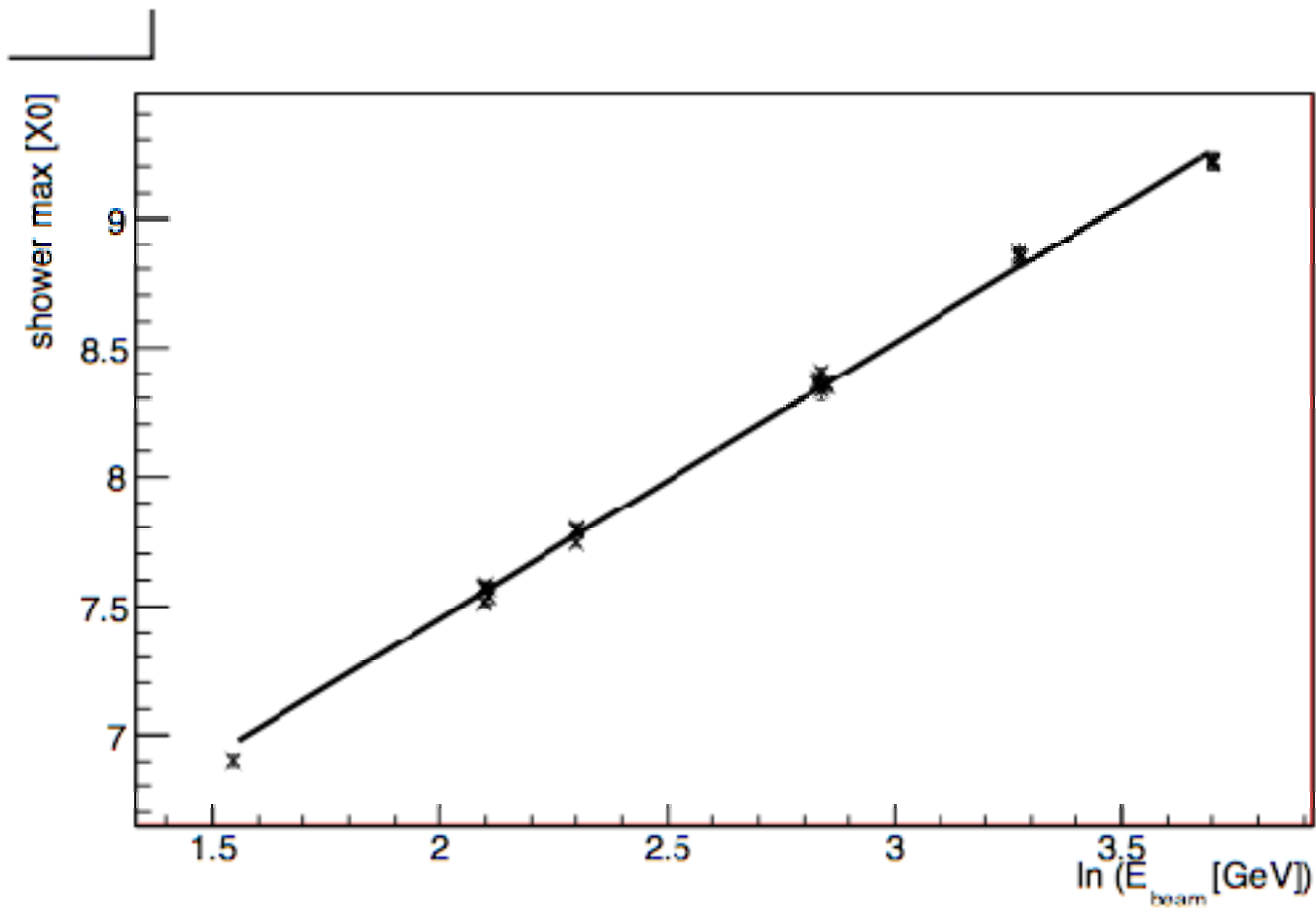
- Comparison the  $\chi^2$  of fit to the data:

e.g. run 300195: 8/NDOF

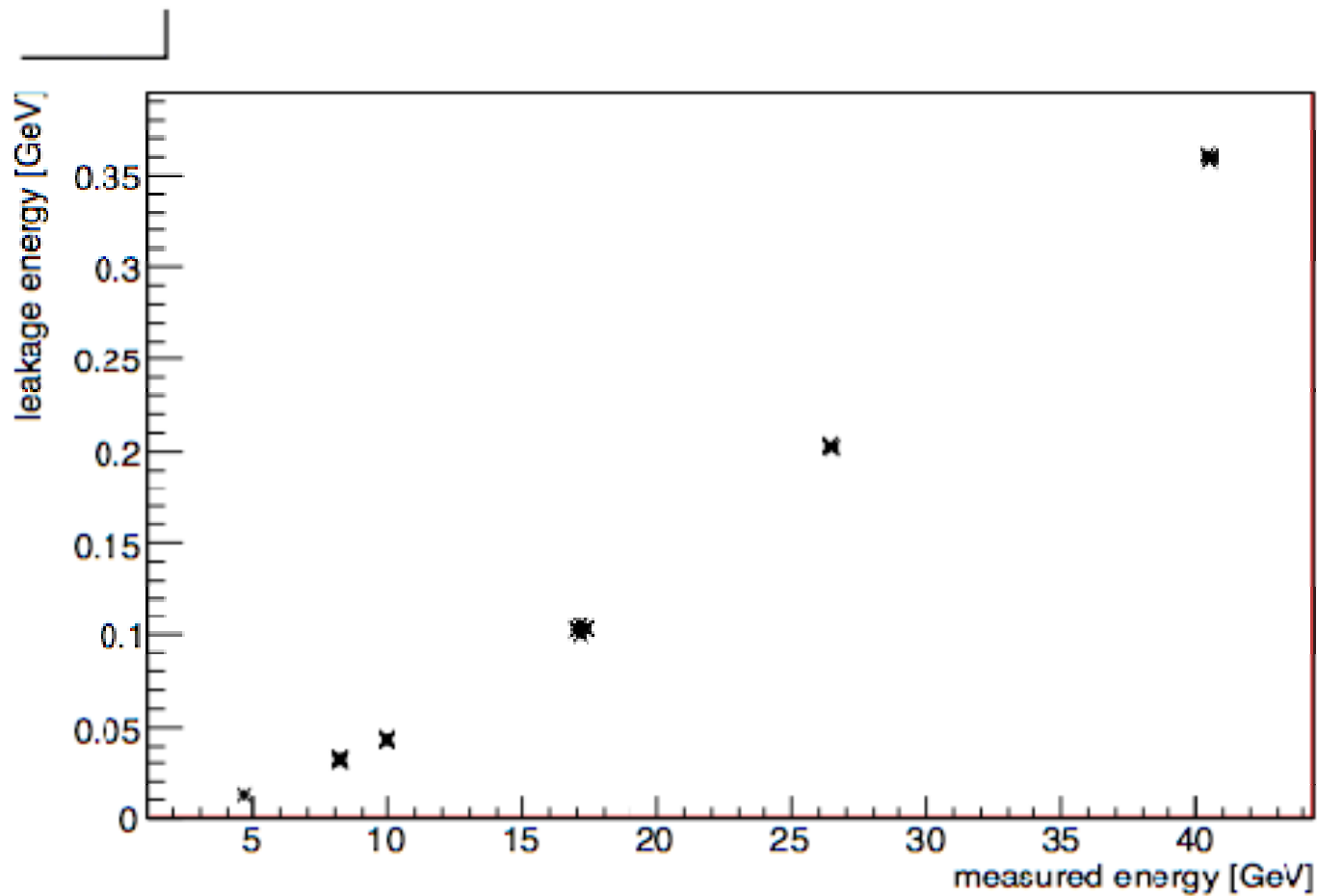
⇒ Close however  $\chi^2$  for fit still a bit high

⇒ I think I need to take noise into account (correction in MC for noise is fine, but fits can not get good  $\chi^2$  if there is too much noise)

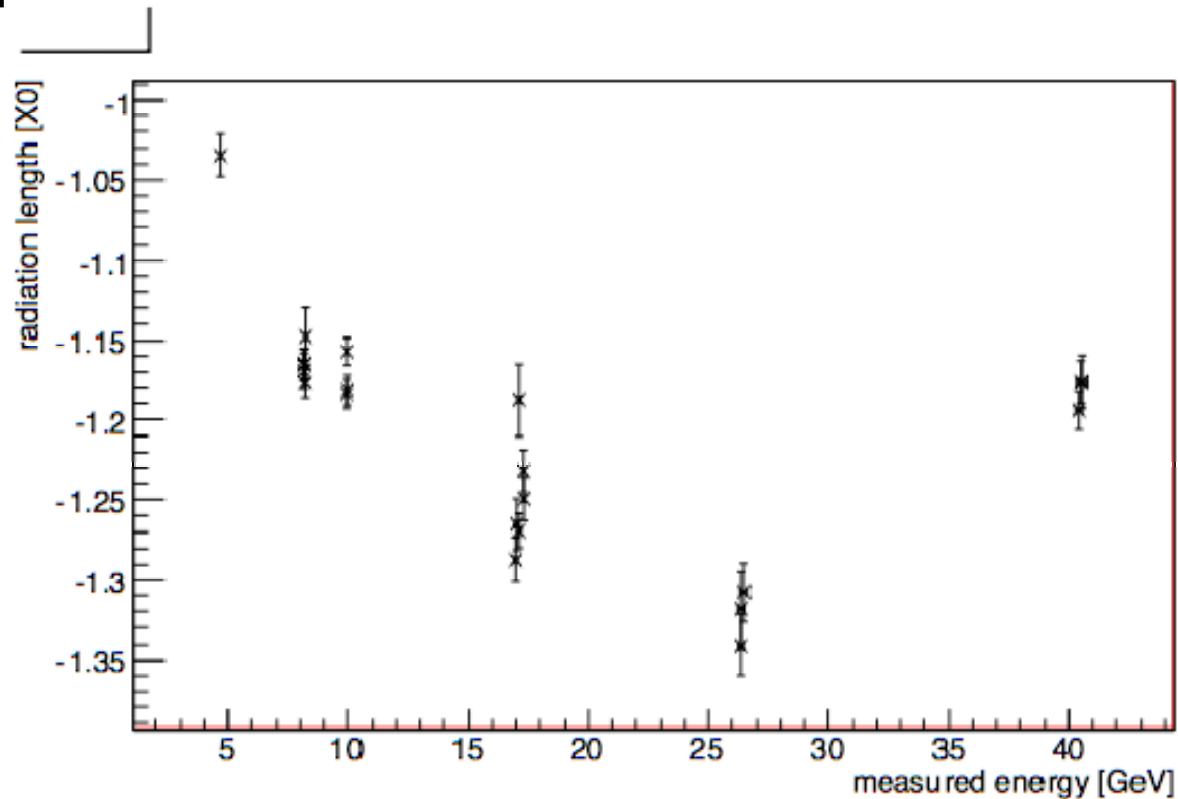
# Extraction of final values: shower maximum



# Extraction of final values: leakage energy



# Extraction of final values: material in front of calo $\beta$



Extraction of  $\beta$  difficult:

- depending on estimate on error
- correlated with  $\gamma$  (here  $\gamma$  is set to 0.5)